



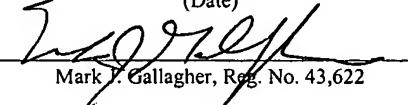
PATENT

Case Docket No. OPTRES.026C2
Date: March 23, 2004

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : Hoffman, et al.
Appl. No. : 10/759,699
Filed : January 19, 2004
For : CORRECTION OF
BIREFRINGENCE IN CUBIC
CRYSTALLINE OPTICAL
SYSTEMS
Examiner : Unknown
Group Art Unit : Unknown

I hereby certify that this correspondence and all
marked attachments are being deposited with the
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Patents, P.O. Box 1450, Alexandria, VA 22313-
1450, on

3/23/04
(Date)

Mark J. Gallagher, Reg. No. 43,622

TRANSMITTAL LETTER

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

Enclosed for filing in the above-identified application are:

- (X) An Information Disclosure Statement.
- (X) A PTO Form 1449 with sixty six (66) references listed with thirty seven (37) enclosed.
- (X) The Commissioner is hereby authorized to charge any additional fees which may be required, or credit any overpayment, to Account No. 11-1410.
- (X) Return prepaid postcard.


Mark J. Gallagher
Registration No. 43,622
Attorney of Record
Customer No. 20,995
(949) 760-0404



INFORMATION DISCLOSURE STATEMENT

Applicant	:	Hoffman, et al.
App. No.	:	10/759,699
Filed	:	January 19, 2004
For	:	CORRECTION OF BIREFRINGENCE IN CUBIC CRYSTALLINE OPTICAL SYSTEMS
Examiner	:	Unknown
Group Art Unit	:	Unknown

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

Enclosed is form PTO-1449 listing sixty six (66) references. Some of these references are cited in U.S. patent application No. 10/071,375, filed February 7, 2002, which is the parent of this continuation application, and is relied upon for an earlier filing date under 35 U.S.C. § 120. Copies of these are not enclosed pursuant to 37 C.F.R. § 1.98(d).

This Information Disclosure Statement is being filed before the receipt of a first Office Action on the merits, and presumably no fee is required in accordance with 37 C.F.R. § 1.97(b)(3). If a first Office Action on the merits was mailed before the mailing date of this Statement, the Commissioner is authorized to charge the fee set forth in 37 C.F.R. § 1.17(p) to Deposit Account No. 11-1410.

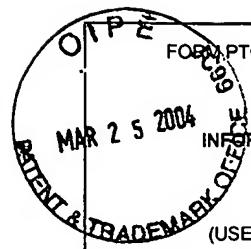
Respectfully submitted,

KNOBBE, MARTENS, OLSON & BEAR, LLP

Dated: 3/23/04

By: 

Mark J. Gallagher
Registration No. 43,622
Attorney of Record
Customer No. 20,995
(949) 760-0404



FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. OPTRES.026C2	APPLICATION NO. 10/759,699
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		
(USE SEVERAL SHEETS IF NECESSARY)		
APPLICANT Hoffman, et al.		
FILING DATE January 19, 2004	GROUP Unknown	

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
1	3,758,201	09/11/73	MacNeille			
2	4,239,329	12/16/80	Matsumoto			
3	4,534,649	08/13/85	Downs			
4	4,576,479	03/18/86	Downs			
5	5,033,830	07/23/91	Jameson			
6	5,537,260	07/16/96	Williamson			
7	6,081,382	06/27/00	Omura			
8	6,084,708	07/04/00	Schuster			
9	6,137,626	10/24/00	Takaoka			
10	6,172,380	01/09/01	Noguchi, et al.			
11	6,195,213	02/27/01	Omura, et al.			
12	6,201,634	03/13/01	Sakuma, et al.			
13	6,252,712	06/26/01	Fürter, et al.			
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15	6,324,003	11/27/01	Martin			
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17	6,683,710	01/27/04	Hoffman, et al.			
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19	2003/0011893	01/16/03	Shiraishi, et al.			
20	2003/0021026	01/2003	Allan, et al.			
21	2003/0025894	02/2003	Owa, et al.			
22	2003/0053036	03/20/03	Fujishima, et al.			
23	2003/0058421	03/27/03	Omura, et al.			
24	2003/0067679	04/10/03	Allan, et al.			
25	2003/0086071	05/08/03	McGuire, Jr.			
26	2003/0086156	05/08/03	McGuire, Jr.			
27	2003/0086171	05/2003	McGuire, Jr.			

EXAMINER	DATE CONSIDERED
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.	

FORM PTO-1449 MAR 25 2004 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)		ATTY. DOCKET NO. OPTRES.026C2	APPLICATION NO. 10/759,699
APPLICANT Hoffman, et al.			
FILING DATE January 19, 2004		GROUP Unknown	

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
28	2003/0168597	09/11/03	Webb, et al.			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
29	EP 0 828 172	03/11/98	European Patent Office				
30	JP 2000-331927	11/30/00	Japan				
31	EP 1 063 684	12/27/00	European Patent Office				
32	EP 1 115 019	07/11/01	European Patent Office				
33	EP 1 139 138	10/04/01	European Patent Office				
34	WO 02/093209	11/21/02	PCT				
35	WO 02/097508	12/05/02	PCT				
36	WO 02/099500	12/12/02	PCT				
37	WO 03/001271	01/03/03	PCT				
38	WO 03/009021	01/30/03	PCT (English abstract only)				
39	WO 03/009050	01/30/03	PCT				
40	WO 03/009062	01/30/03	PCT (English abstract only)				

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41	Rudolf Kingslake, <i>Lens Design Fundamentals</i> , 1978, pp. 320-321, Academic Press, Inc., San Diego, California
42	A. Hand, "157 nm Optics Demand a Bag of Tricks", Semiconductor International http://www.e-insite.net/semiconductor/index.asp?layout=article&stt (February 2001)
43	Shiraishi, et al., "Current Status of Nikon's Investigation on CaF ₂ Intrinsic Birefringence", International-SEMA TECH . Calcium Fluoride Birefringence Workshop, July 18, 2001, pp. 1-15
44	Burnett, et al., "Intrinsic Birefringence in Calcium Fluoride", National Institute of Standards and Technology, Gaithersburg, Maryland 20899, submitted for publication to Physical Review Letters (May 11, 2001), pp. 1-12
45	Burnett, et al., "Minimizing spatial-dispersion-induced birefringence in crystals for precision optics by using mixed crystals of materials with opposite sign of the birefringence", National Institute of Standards and Technology, Gaithersburg, Maryland 20899, http://physics.nist.gov/Divisions/Div842/Gp3/DUVMatChar/birefring.nt (July 12, 2001), pp. 1-3
46	U.S. Provisional Patent Application 60/306,206, filed July 18, 2001 which is a priority document for WO 03/009050

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C 1 P FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. OPTRES.026C2	APPLICATION NO. 10/759,699
MAR 25 2004 INFORMATION DISCLOSURE STATEMENT BY APPLICANT			
(USE SEVERAL SHEETS IF NECESSARY)			
	APPLICANT Hoffman, et al.		
	FILING DATE January 19, 2004	GROUP Unknown	

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)		
	47 U.S. Provisional Patent Application 60/308,844, filed August 1, 2001 (Japanese Language)		
	48 English translation of Provisional Application No. 60/308,844, filed August 1, 2001 (filed in USPTO on October 23, 2002)		
	49 Burnett, et al., "Intrinsic birefringence in calcium fluoride and barium fluoride", Physical Review B, Vol. 64, May 14, 2001, pp. 241102-1-241102-4		
	50 Burnett, et al., "Intrinsic Birefringence in 157 nm Materials", Proceedings of the International Symposium on 157NM Lithography, Dana Point, CA, May 15, 2001, XP002218849, pp. 1-13		
	51 Burnett, et al., "Intrinsic Birefringence in 157 nm Materials", Proc 2 nd , Intl. Sump on 157 nm Lithography, 2001, pp. 1-13, International SEMATECH, Austin, Texas		
	52 Burnett, et al., "Intrinsic Birefringence in Calcium Fluoride", preprinted handed out at 2 nd International Symposium on 157NM Lithography, Dana Point, CA, May 15, 2001, XP002232195, pp. 1-17		
	53 D. Krähmer, "Intrinsic Birefrinence in CaF ₂ " at CaF ₂ Birefringence Worksho[, Intl SEMATECH, July 18, 2001, pp. 1-9		
	54 Morton, et al., "Testing Optical Damage for 157 nm Lithography", Semiconductor International, http://www.e-insite.net/semiconductor/index.asp?layout=article&stt (February 2002)		
	55 Burnett, et al., "Alternative Materials Development (LITJ216) Final Report - Stress Birefringence, Intrinsic Birefringence, and Index Properties of 157 nm Refractive Materials", International SEMATECH, February 28, 2002, 33 pages		
	56 J. Dyson, "Unit magnification optical system without Seidel aberrations," J. Opt. Soc. Am., Vol. 49, 1959, p. 713 as described by R. Kingslake, "Lens Design Fundamentals," Institute of Optics, University of Rochester, Academic Press, Inc., 1978, pp. 320-321		
	57 Yeh, et al., "Optics of Liquid Crystal Displays", John Wiley & Sons, Inc., New York, 1999, pp. 380-385		
	58 U.S. Patent Application 10/178,601, filed June 20, 2002 (OPTRES.002A)		
	59 U.S. Patent Application 10,178,937, filed June 20, 2002 (OPTRES.003A)		
	60 U.S. Patent Application 10/178,621, filed June 20, 2002 (OPTRES.004A)		
	61 U.S. Patent Application 10/178,935, filed June 20, 2002 (OPTRES.006A)		
	62 U.S. Patent Application 10/331,159, filed December 26, 2002 (OPTRES.007A)		
	63 U.S. Patent Application 10/331,101, filed December 26, 2002 (OPTRES.012A)		
	64 U.S. Patent Application 10/331,103, filed December 26, 2002 (OPTRES.013A)		
	65 U.S. Patent Application 10/371,266, filed February 20, 2003 (OPTRES.026C1)		
	66 U.S. Patent Application 10/371,269, filed February 20, 2003 (OPTRES.026DV1)		

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